



Monitoring System for Industry 4.0: AI-Driven, Data Analysis and Health Maintenance

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Message from the Guest Editors

With the development of IoT and “Industry 4.0”, industrial systems become more intelligent and complex, and monitoring systems’ health is very important to guarantee stability, security, and economy. This shift also concerns diverse research areas, e.g., detection of abnormal data, unhealthy status, fault diagnosis, adversarial attacks, robustness analysis, and so on. On the other hand, with the development of sensor systems, large quantities of data have become easily available, bringing challenges to industrial systems’ condition monitoring.

This Research Topic aims to select potential contributions related to advanced theoretical findings, technologies, algorithms, and industrial applications in the monitoring of industrial systems’ health. Subtopics of interest include:

- Machine learning; Deep learning; Data Mining; Big data analytics; Graph theory.
- Data cleaning; Abnormal data detection; Anomaly detection; Condition monitoring; Fault diagnosis.





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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